26. The electronic system of claim **25**, wherein the processor is interoperable with the memory to calculate a uniformity of the thickness of the first layer.

27-28. (canceled)

29. A method, comprising:

determining a thickness of a first layer of a structure based on processing an original image of the structure, the first layer including a first boundary and a second boundary, the original image including a representation of the first boundary, the second boundary being substantially indistinguishable in the original image, the determining including,

segmenting the original image into a plurality of partial images, at least some of the partial images including separate portions of the first boundary representation;

adjusting relative arrangements of the plurality of partial images to generate a first image of the structure, the first image including an aligned arrangement of the first boundary representation portions, the aligned arrangement being aligned with an axis of the first image; and

filtering the first image to generate a second image of the structure;

extracting the second boundary from the second image;

determining the thickness of the first layer based on a determined distance between the first boundary and the second boundary.

30. The method of claim 29, wherein,

the representation of the first boundary in the original image is a nonlinear line, and

the axis line extends in a first direction in the first image. **31-32**. (canceled)

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